



512Kx16 SRAM MODULE *ADVANCED**

FEATURES

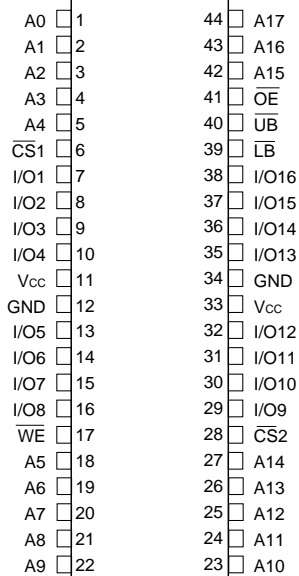
- Access Times 17, 20, 25, 35ns
- MIL-STD-883 Compliant Devices Available
- Packaging
 - 44 pin Ceramic SOJ (Package 102)
 - 44 lead Ceramic Flatpack (Package 209)
- Organized as two banks of 256Kx16
- Data Byte Control:
 - Lower Byte (\overline{LB}) = I/O1-8
 - Upper Byte (\overline{UB}) = I/O9-16
- Data I/O Compatible with 3.3V devices
- 2V Minimum Data Retention for battery back up operation
- Commercial, Industrial and Military Temperature Range
- 5 Volt Power Supply (3.3V parts also available)
- Low Power CMOS
- TTL Compatible Inputs and Outputs

* This data sheet describes a product that may or may not be under development and is subject to change or cancellation without notice.

PIN CONFIGURATION FOR WS512K16-XXX

44 CSOJ 44 FLATPACK

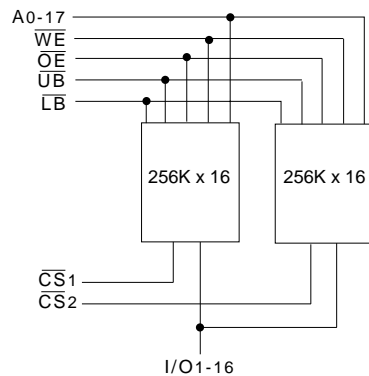
TOP VIEW



PIN DESCRIPTION

A0-17	Address Inputs
\overline{LB}	Lower-Byte Control (I/O1-8)
\overline{UB}	Upper-Byte Control (I/O9-16)
I/O1-16	Data Input/Output
\overline{CS}_{1-2}	Chip Select
\overline{OE}	Output Enable
\overline{WE}	Write Enable
Vcc	+5.0V Power
GND	Ground
NC	No Connection

BLOCK DIAGRAM



**TRUTH TABLE**

\overline{CS}_1	\overline{CS}_2	\overline{WE}	\overline{OE}	\overline{LB}	\overline{UB}	Mode	Data I/O		Power
							I/O ₁₋₈	I/O ₉₋₁₆	
H	H	X	X	X	X	Not Select	High Z	High Z	Standby
L	H	H	H	X	X	Output Disable	High Z	High Z	Active
H	L								
L	H	X	X	H	H				
H	L								
H	L	H	L	L	H	Read	Data Out	High Z	Active
L	H			H	L		High Z	Data Out	
L	L			L	L		Data Out	Data Out	
H	L	L	X	L	H	Write	Data In	High Z	Active
L	H			H	L		High Z	Data In	
L	L			L	L		Data In	Data In	

ABSOLUTE MAXIMUM RATINGS

Parameter	Symbol	Min	Max	Unit
Operating Temperature	T _A	-55	+125	°C
Storage Temperature	T _{STG}	-65	+150	°C
Signal Voltage Relative to GND	V _G	-0.5	V _{CC} +0.5	V
Junction Temperature	T _J		150	°C
Supply Voltage	V _{CC}	-0.5	7.0	V

RECOMMENDED OPERATING CONDITIONS

Parameter	Symbol	Min	Max	Unit
Supply Voltage	V _{CC}	4.5	5.5	V
Input High Voltage	V _{IH}	2.2	V _{CC} + 0.3	V
Input Low Voltage	V _{IL}	-0.3	+0.8	V
Operating Temp. (Mil.)	T _A	-55	+125	°C

CAPACITANCE(T_A = +25°C)

Parameter	Symbol	Condition	Max	Unit
Input capacitance	C _{IN}	V _{IN} = 0V, f = 1.0MHz	25	pF
Output capacitance	C _{OUT}	V _{OUT} = 0V, f = 1.0MHz	25	pF

This parameter is guaranteed by design but not tested.

DC CHARACTERISTICS(V_{CC} = 5.0V, GND = 0V, T_A = -55°C to +125°C)

Parameter	Sym	Conditions			Units
			Min	Max	
Input Leakage Current	I _{LI}	V _{CC} = 5.5, V _{IN} = GND to V _{CC}		10	μA
Output Leakage Current	I _{LO}	$\overline{CS} = V_{IH}, \overline{OE} = V_{IH}, V_{OUT} = GND \text{ to } V_{CC}$		10	μA
Operating Supply Current	I _{CC}	$\overline{CS} = V_{IL}, \overline{OE} = V_{IH}, f = 5\text{MHz}, V_{CC} = 5.5$		290	mA
Standby Current	I _{SB}	$\overline{CS} = V_{IH}, \overline{OE} = V_{IH}, f = 5\text{MHz}, V_{CC} = 5.5$		30	mA
Output Low Voltage	V _{OL}	I _{OL} = 8mA, V _{CC} = 4.5		0.4	V
Output High Voltage	V _{OH}	I _{OH} = -4.0mA, V _{CC} = 4.5	2.4		V

NOTE: DC test conditions: V_{IH} = V_{CC} - 0.3V, V_{IL} = 0.3V**DATA RETENTION CHARACTERISTICS**(T_A = -55°C to +125°C)

Parameter	Symbol	Conditions				Units
			Min	Typ	Max	
Data Retention Supply Voltage	V _{DR}	$\overline{CS} \geq V_{CC} - 0.2V$	2.0		5.5	V
Data Retention Current	I _{CCDR1}	V _{CC} = 3V		2.0	12.0*	mA

* Also available in Low Power version. Please call factory for information.



AC CHARACTERISTICS

(Vcc = 5.0V, GND = 0V, TA = -55°C to +125°C)

Table with 11 columns: Parameter, Symbol, -17 (Min, Max), -20 (Min, Max), -25 (Min, Max), -35 (Min, Max), Units. Rows include Read Cycle Time, Address Access Time, Output Hold from Address Change, etc.

1. This parameter is guaranteed by design but not tested.

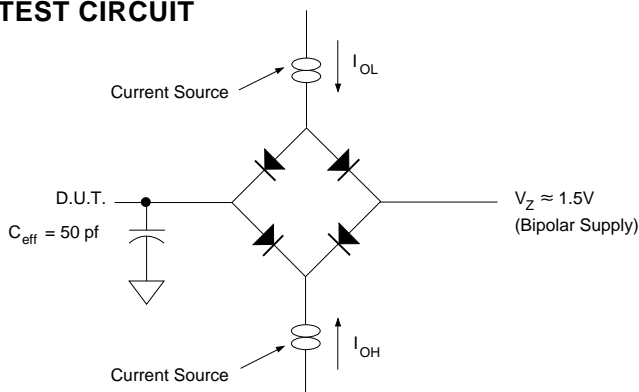
AC CHARACTERISTICS

(Vcc = 5.0V, GND = 0V, TA = -55°C to +125°C)

Table with 11 columns: Parameter, Symbol, -17 (Min, Max), -20 (Min, Max), -25 (Min, Max), -35 (Min, Max), Units. Rows include Write Cycle Time, Chip Select to End of Write, Address Valid to End of Write, etc.

1. This parameter is guaranteed by design but not tested.

AC TEST CIRCUIT



AC TEST CONDITIONS

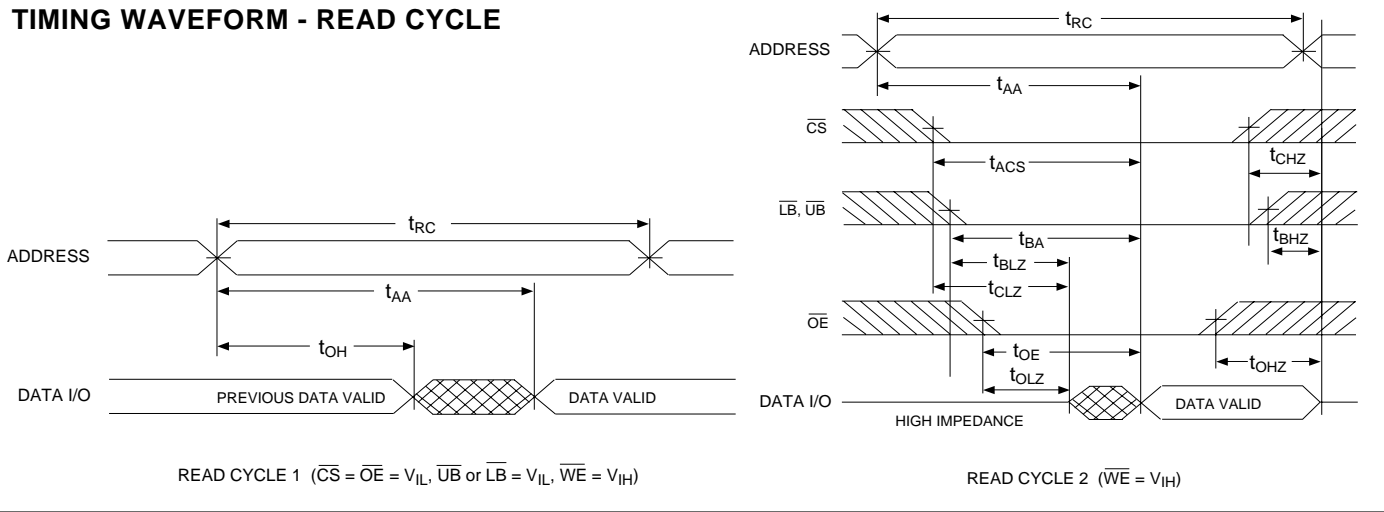
Table with 3 columns: Parameter, Typ, Unit. Rows include Input Pulse Levels, Input Rise and Fall, Input and Output Reference Level, Output Timing Reference Level.

NOTES:

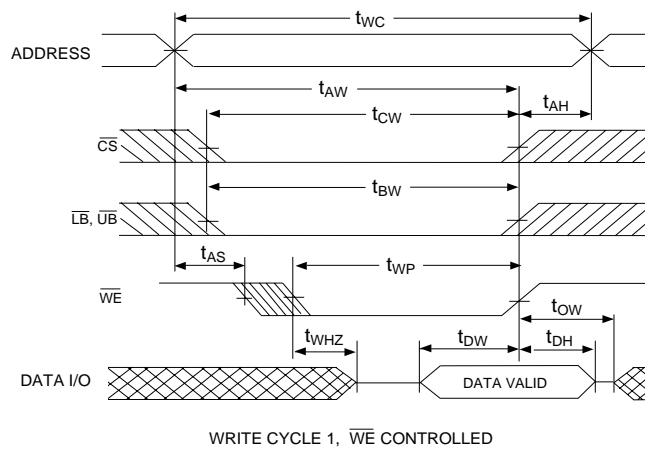
Vz is programmable from -2V to +7V. IOL & IOH programmable from 0 to 16mA. Tester Impedance Z0 = 75 Ω. Vz is typically the midpoint of VOH and VOL. IOL & IOH are adjusted to simulate a typical resistive load circuit. ATE tester includes jig capacitance.



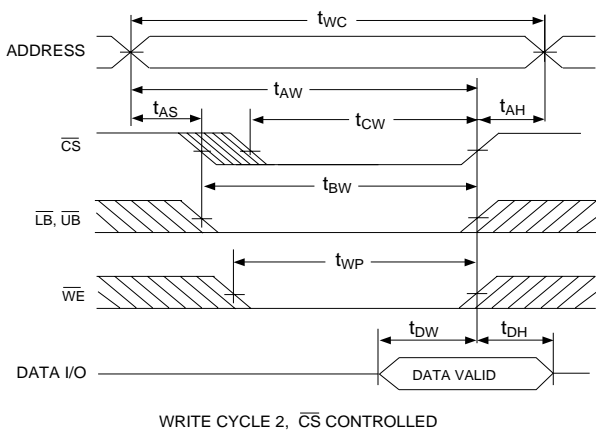
TIMING WAVEFORM - READ CYCLE



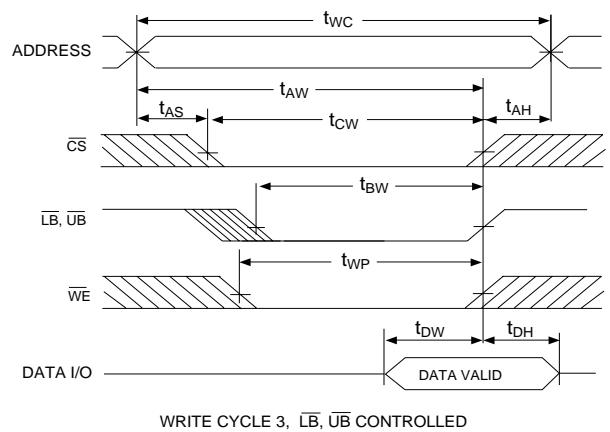
WRITE CYCLE - \overline{WE} CONTROLLED



WRITE CYCLE - \overline{CS} CONTROLLED

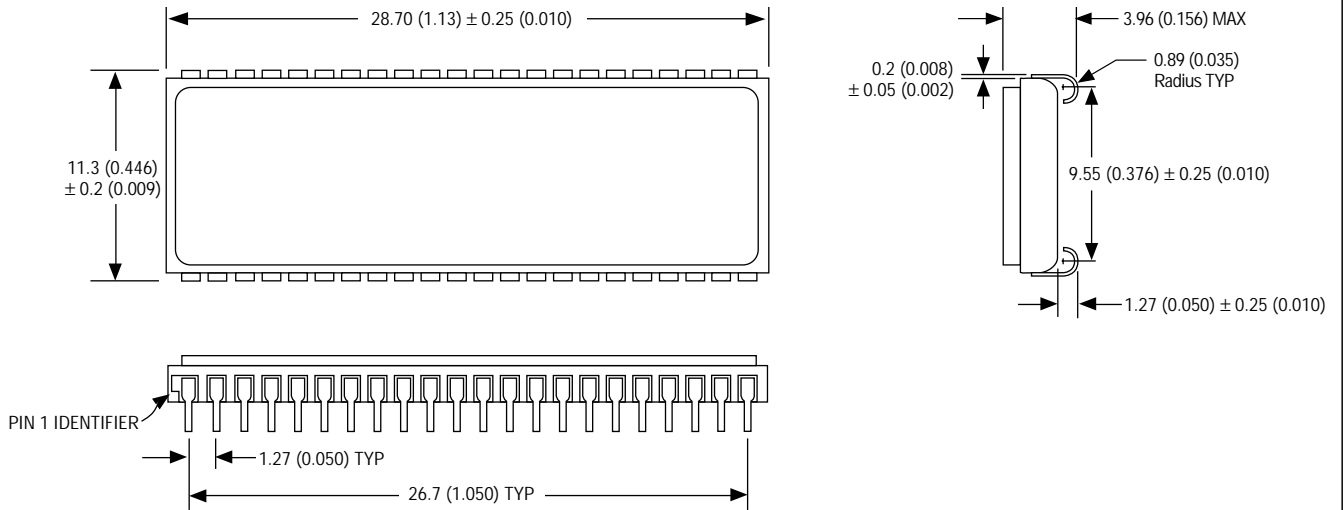


WRITE CYCLE - \overline{LB} , \overline{UB} CONTROLLED



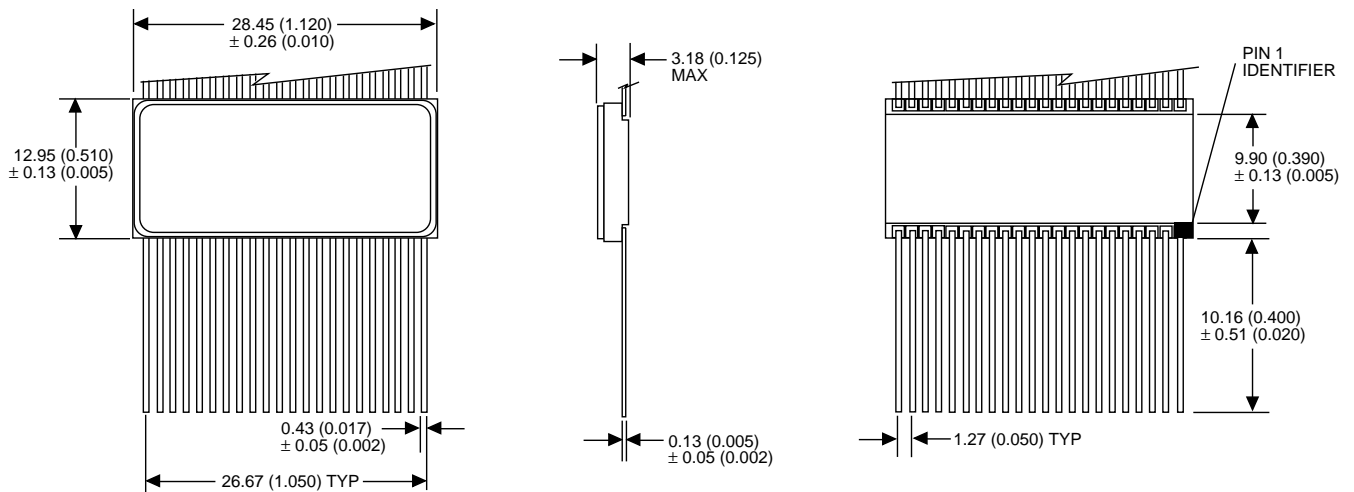


PACKAGE 102: 44 LEAD, CERAMIC SOJ



ALL LINEAR DIMENSIONS ARE MILLIMETERS AND PARENTHETICALLY IN INCHES

PACKAGE 209: 44 LEAD, CERAMIC FLAT PACK



ALL LINEAR DIMENSIONS ARE MILLIMETERS AND PARENTHETICALLY IN INCHES



ORDERING INFORMATION

W S 512K16 - XX X X X

